TOSHIBA Power Transistor Module Silicon NPN Epitaxial Type (Four Darlington Power Transistors in One)

# **MP4021**

**High Power Switching Applications** 

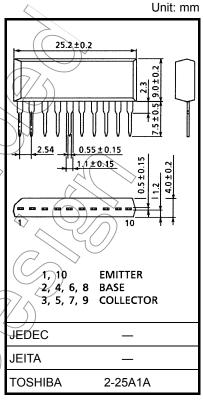
Hammer Drive, Pulse Motor Drive and Inductive Load Switching

- Small package by full molding (SIP 10 pins)
- High collector power dissipation (4-device operation)
   PT = 4 W (Ta = 25°C)
- High collector current: IC (DC) = 2 A (max)
- High DC current gain:  $h_{FE} = 2000$  (min) ( $V_{CE} = 2 \text{ V}$ ,  $I_{C} = 1 \text{ A}$ )
- Zener diode included between collector and base.

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Collector-base voltage		$V_{CBO}$	85	V	
Collector-emitter voltage		V <sub>CEO</sub>	100 ± 15	У	
Emitter-base voltage		V <sub>EBO</sub>	8	//	
Collector current	DC	Ic	2		
	Pulse	ICP	)) 3	A	
Continuous base current		lβ ∨	0.5	A	
Collector power dissipation		PC	2.0	NX.	
(1-device operation)			2.0	VV	
Collector power dissipati	on	PT	4.07	,	
(4-device operation)		~ ` ` )	(*// 5)	VV	
Junction temperature		Tj	150	°C	
Storage temperature ran	ge	T <sub>stg</sub>	-55 to 150	°C	

**Industrial Applications** 

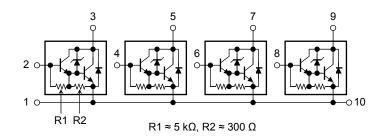


Weight: 2.1 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design/the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### **Array Configuration**



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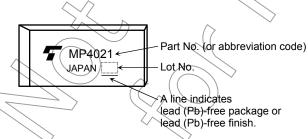
#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit	
Thermal resistance from junction to ambient	ΣR <sub>th (j-a)</sub>	31.3	°C/W	
(4-device operation, Ta = 25°C)	,			
Maximum lead temperature for soldering purposes	TL	260	°C	
(3.2 mm from case for 10 s)				

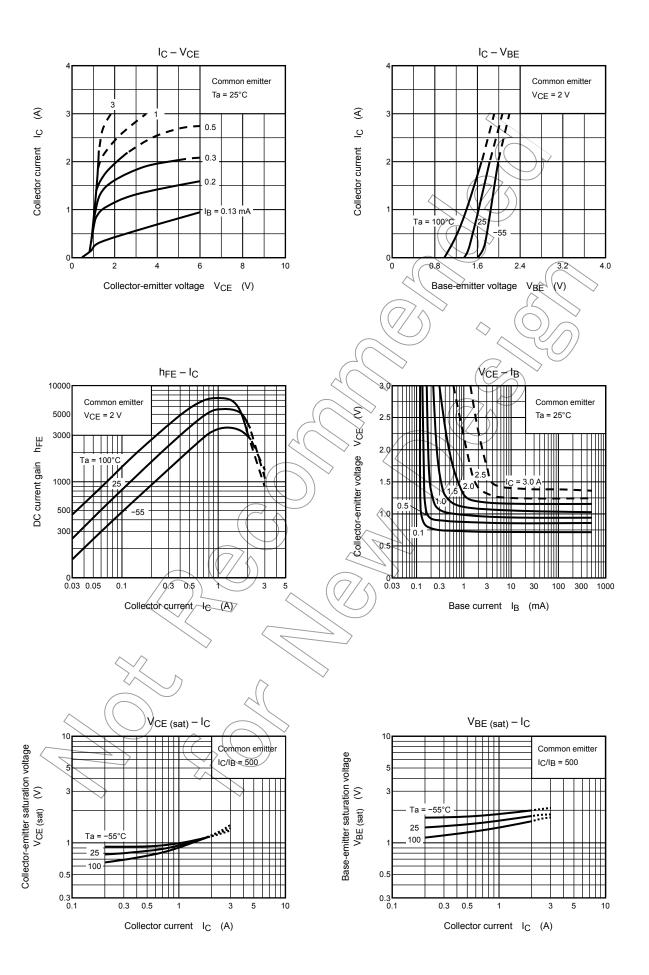
### **Electrical Characteristics (Ta = 25°C)**

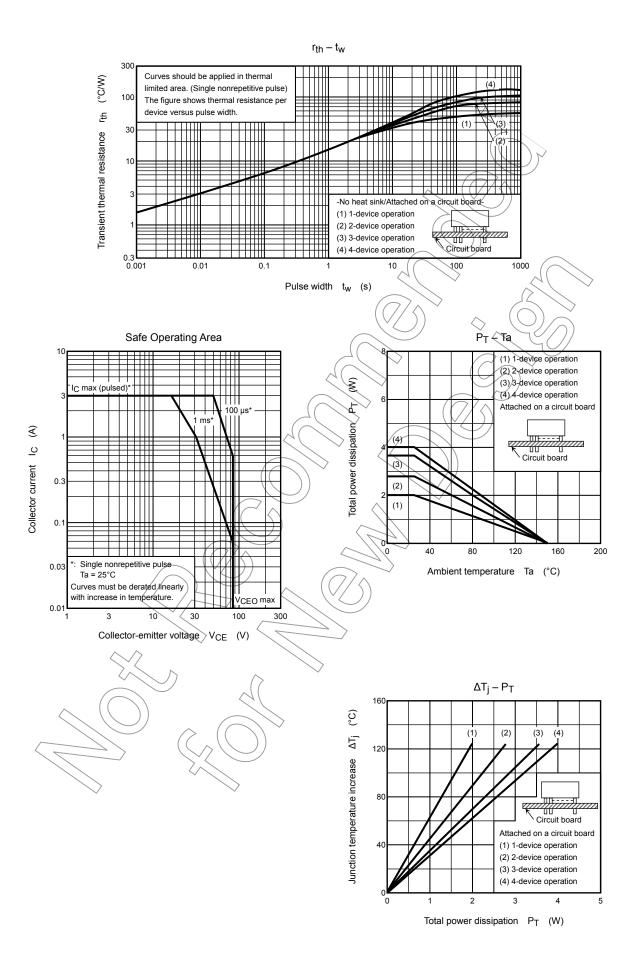
Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Collector cut-off current		I <sub>CBO</sub>	V <sub>CB</sub> = 80 V, I <sub>E</sub> = 0 A	_		10	μΑ	
Collector cut-off current		I <sub>CEO</sub>	V <sub>CE</sub> = 80 V, I <sub>B</sub> = 0 A	/	7	10	μΑ	
Emitter cut-off current		I <sub>EBO</sub>	V <sub>EB</sub> = 8 V, I <sub>C</sub> = 0 A	0.8	/-/	> 4.0	mA	
Collector- emitter breakdown voltage		V (BR) CEO	I <sub>C</sub> = 10 mA, I <sub>E</sub> = 0 A	85	100	) 115	V	
DC current gain		h <sub>FE</sub>	V <sub>CE</sub> = 2 V, (C = 1 A	2000	90)	_	_	
Saturation voltage	Collector-emitter	V <sub>CE</sub> (sat)	I <sub>C</sub> = 1 A, I <sub>B</sub> = 1 mA		> _	1.5	V	
	Base-emitter	V <sub>BE (sat)</sub>	I <sub>C</sub> = 1 A, I <sub>B</sub> = 1 mA	77)	_	2.0		
Transition frequenc	cy .	f <sub>T</sub>	V <sub>CE</sub> = 2 V, I <sub>C</sub> = 0.5 A	\ _	100	_	MHz	
Collector output capacitance		C <sub>ob</sub>	VCB = 10 V, IE = 0 A, T = 1 MHz	/ _	20	_	pF	
Switching time	Turn-on time	ton	Input ⇒ Output	_	0.45	_		
	Storage time	tstg	20 μs B2 W V <sub>CC</sub> = 30 V	_	2.0	_	μs	
	Fall time	t <sub>f</sub>	t <sub>B1</sub> = 1 <sub>B2</sub> = 1 mA, duty cycle ≤ 1%	_	0.4	_		

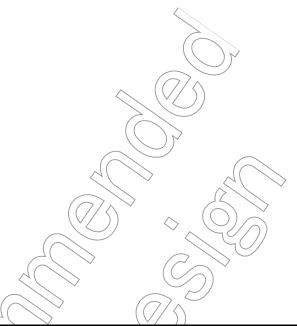
## Marking



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2006-10-27